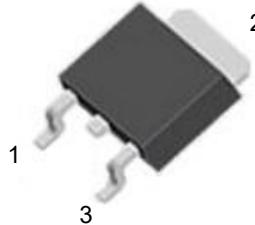
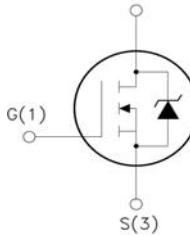


XXW10N50 Features <ul style="list-style-type: none"> <input type="checkbox"/> Low Intrinsic Capacitances <input type="checkbox"/> Excellent Switching Characteristics <input type="checkbox"/> Extended Safe Operating Area <input type="checkbox"/> Unrivalled Gate Charge : 28 nC (Typ.) <input type="checkbox"/> $V_{DSS}=500V, I_D=10A$ <input type="checkbox"/> Lower $R_{DS(on)}$: 0.70 Ω (Max) @ $V_G=10V$ <input type="checkbox"/> 100% Avalanche Tested 	T0-252   1. Gate (G) 2. Drain (D) 3. Source (S)
--	---

Absolute Maximum Ratings ($T_a=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage	500	V
I_D	Drain Current	$T_j=25^\circ C$	10
		$T_j=100^\circ C$	5.7
V_{GSS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note1)	190	mJ
I_{AR}	Avalanche Current (note2)	9.0	A
P_D	Power Dissipation ($T_j=25^\circ C$)	30	W
T_j	Junction Temperature(Max)	150	°C
T_{stg}	Storage Temperature	-55~+150	°C
TL	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	°C

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance,Junction to Case	-	1.88	°C/W
$R_{\theta JA}$	Thermal Resistance,Junction to Ambient	-	62.5	°C/W

Electrical Characteristics (Ta=25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max	Units
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	ID=250 μ A, VGS=0	500	--	--	V
△BV _{DSS} / △T _J	Breakdown Voltage Temperature Conficient	I _D =250 μ A ,Reference to 25°C	--	0.55	--	V/°C
IDSS	Zero Gate Voltage Drain Current	Vds=500V, Vgs=0V	--	--	1	μ A
		Vds=400V, Tc=125°C			10	μ A
IGSSF	Gate-body leakage Current, Forward	Vgs=+30V, Vds=0V	--	--	100	nA
IGSSR	Gate-body leakage Current, Reverse	Vgs=-30V, Vds=0V	--	--	-100	nA

On Characteristics

V _{GS(th)}	Date Threshold Voltage	I _d =250uA,V _{ds} =V _{gs}	2	--	4	V
R _{DS(on)}	Static Drain-Source On-Resistance	I _d =4.5A,V _{gs} =10V	--	0.65	0.70	Ω

Dynamic Characteristics

C _{iss}	Input Capacitance	VDS=25V, VGS=0, f=1.0MHz	--	1012	--	pF
C _{oss}	Output Capacitance		--	160	--	pF
C _{rss}	Reverse Transfer Capacitance		--	20	--	pF

Switching Characteristics

T _{d(on)}	Turn-On Delay Time	VDD=250V, ID=9A, RG=25 Ω (Note 3,4)	--	25	60	nS
T _r	Turn-On Rise Time		--	95	200	nS
T _{d(off)}	Turn-Off Delay Time		--	55	120	nS
T _f	Turn-Off Fall Time		--	60	130	nS
Q _g	Total Gate Charge	VDS=400, VGS=10V, ID=9A (Note 3,4)	--	28	36	nC
Q _{gs}	Gate-Source Charge		--	7	--	nC
Q _{gd}	Gate-Drain Charge			12.5	--	nC

Drain-Source Diode Characteristics and Maximum Ratings

I _s	Maximun Continuous Drain-Source Diode Forward Current	--	--	9	A
I _{SM}	Maximun Plused Drain-Source DiodeForwad Current	--	--	36	A
V _{SD}	Drain-Source Diode Forward Voltage	Id=9A	--	1.45	V
trr	Reverse Recovery Time	I _s =9.0A, V _{GS} =0V di _f /dt=100A/ μ s (Note3)	--	300	--
Qrr	Reverse Recovery Charge		--	2.2	--

*Notes 1, L=8mH, IAS=9A, VDD=50V, RG=25Ω, Starting TJ =25°C

2, Repetitive Rating : Pulse width limited by maximum junction temperature

3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%

4, Essentially Independent of Operating Temperature

Typical Characteristics

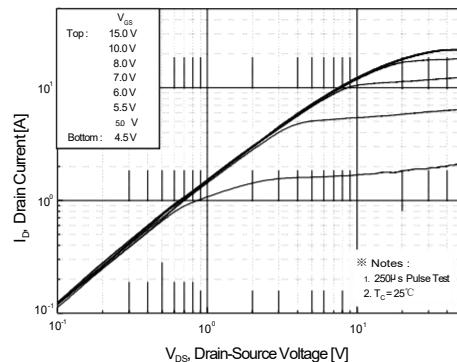


Figure 1. On-Region Characteristics

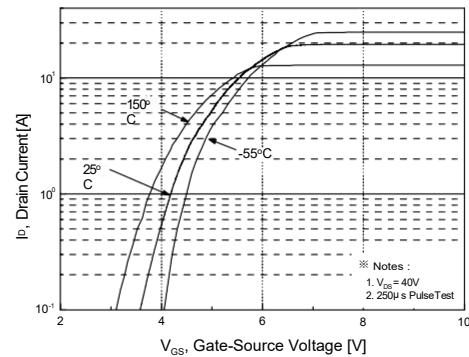


Figure 2. Transfer Characteristics

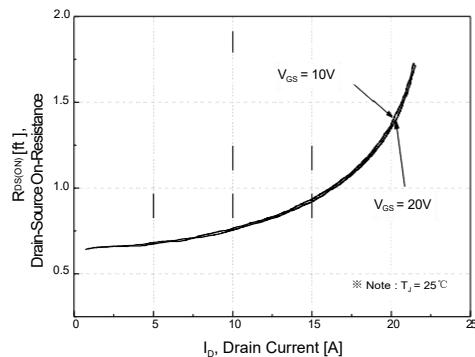


Figure 3. On-Resistance Variation vs
Drain Current and Gate Voltage

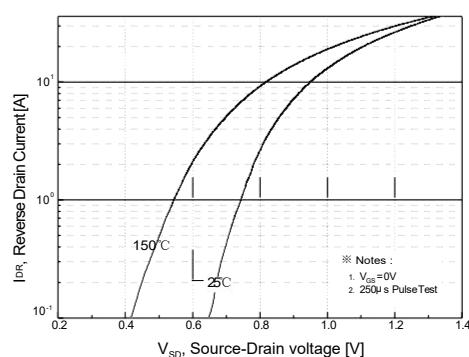


Figure 4. Body Diode Forward Voltage
Variation with Source Current
and Temperature

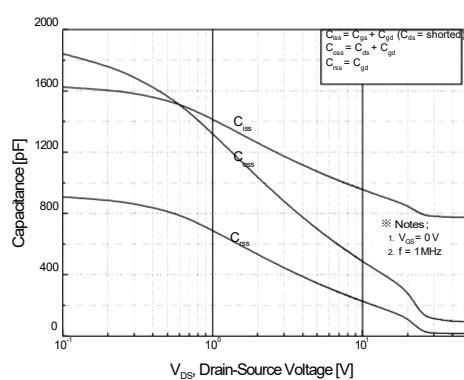


Figure 5. Capacitance Characteristics

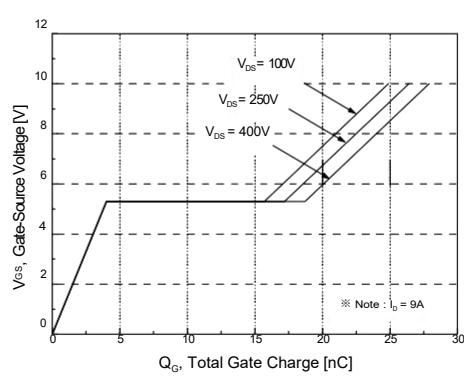
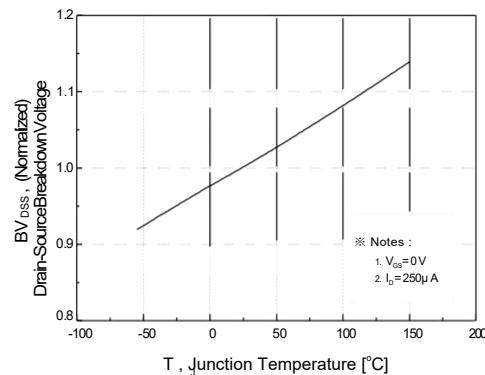
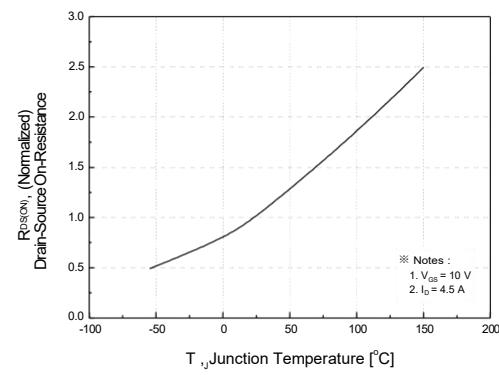


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)


**Figure 7. Breakdown Voltage Variation
vs Temperature**



**Figure 8. On-Resistance Variation
vs Temperature**

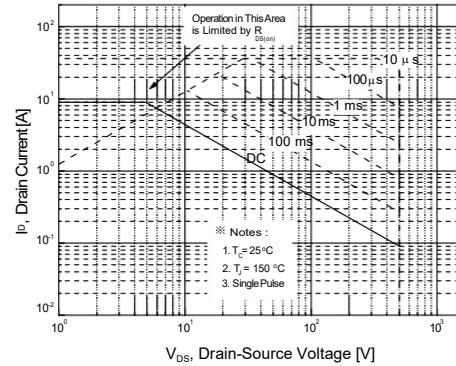
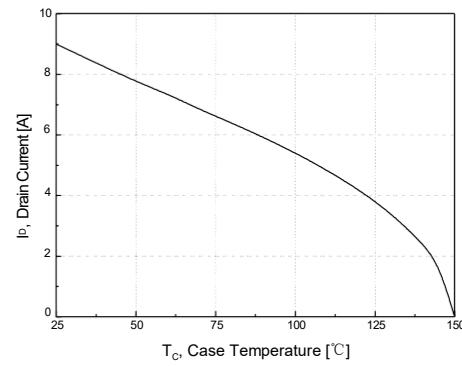


Figure 9-2. Maximum Safe Operating Area



**Figure 10. Maximum Drain Current
vs Case Temperature**

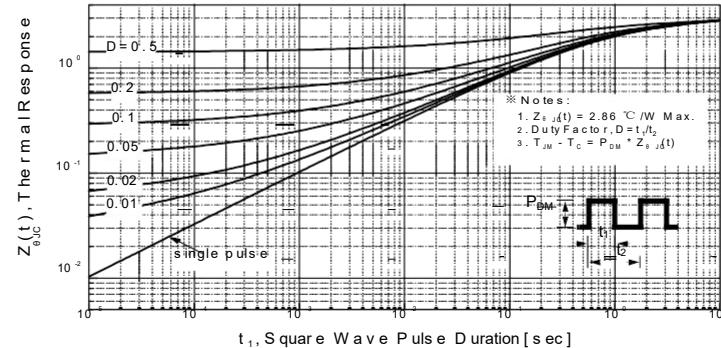
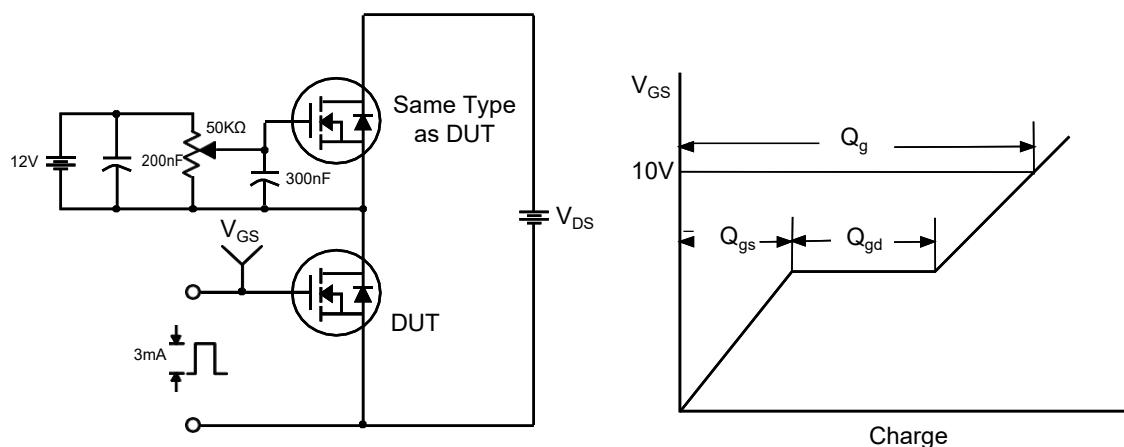
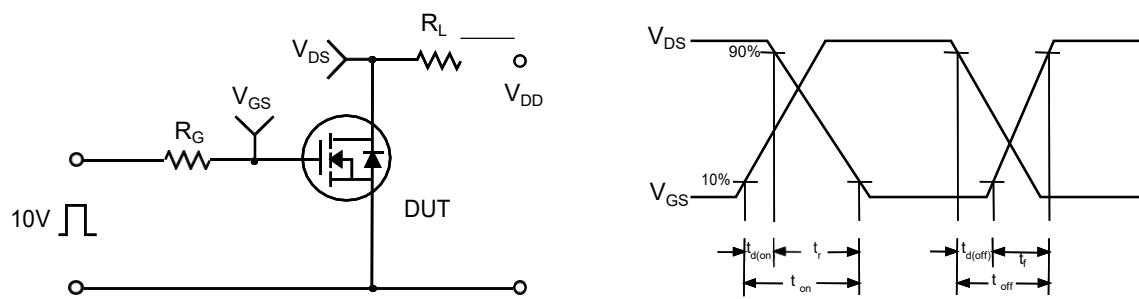
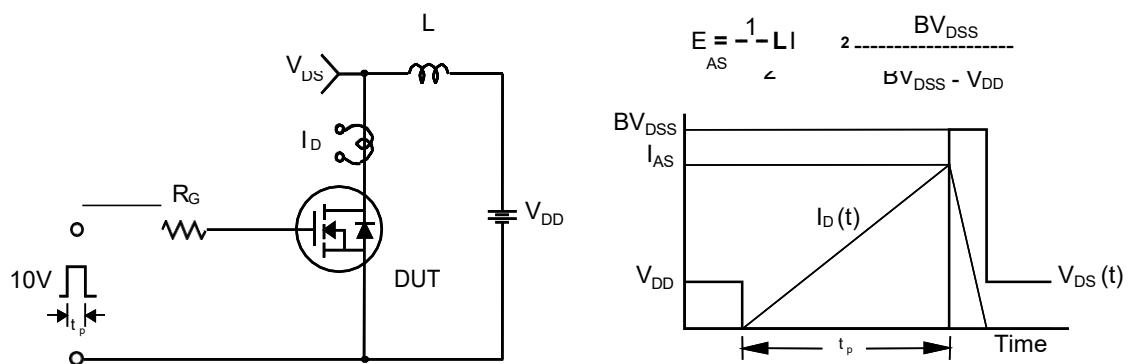
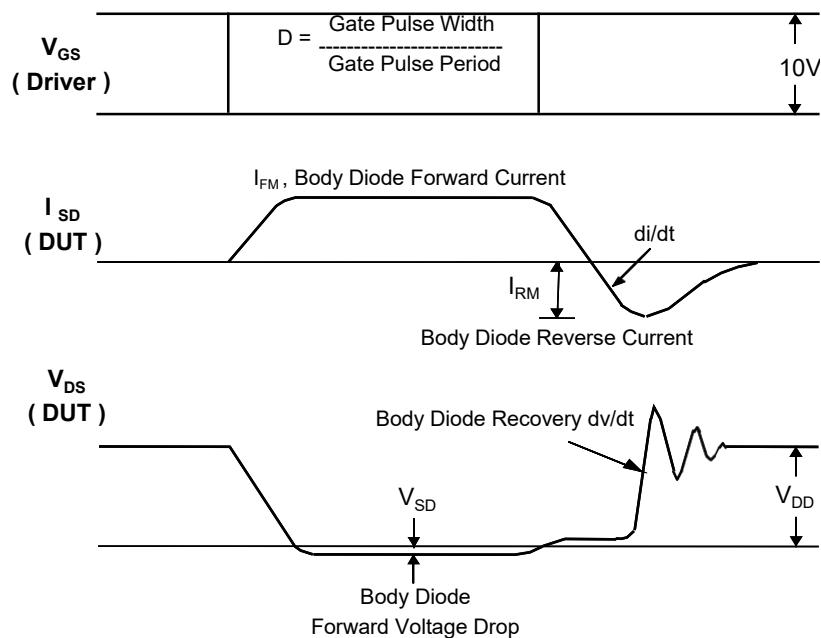
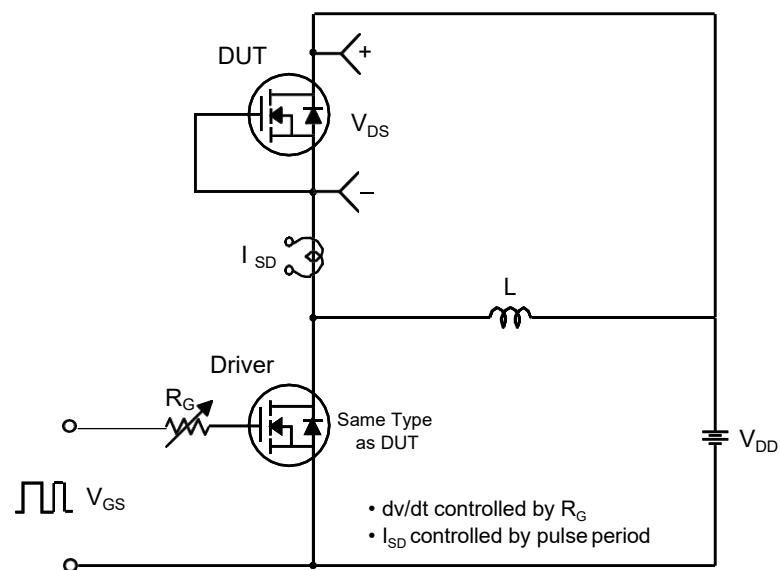


Figure 11-2. Transient Thermal Response Curve

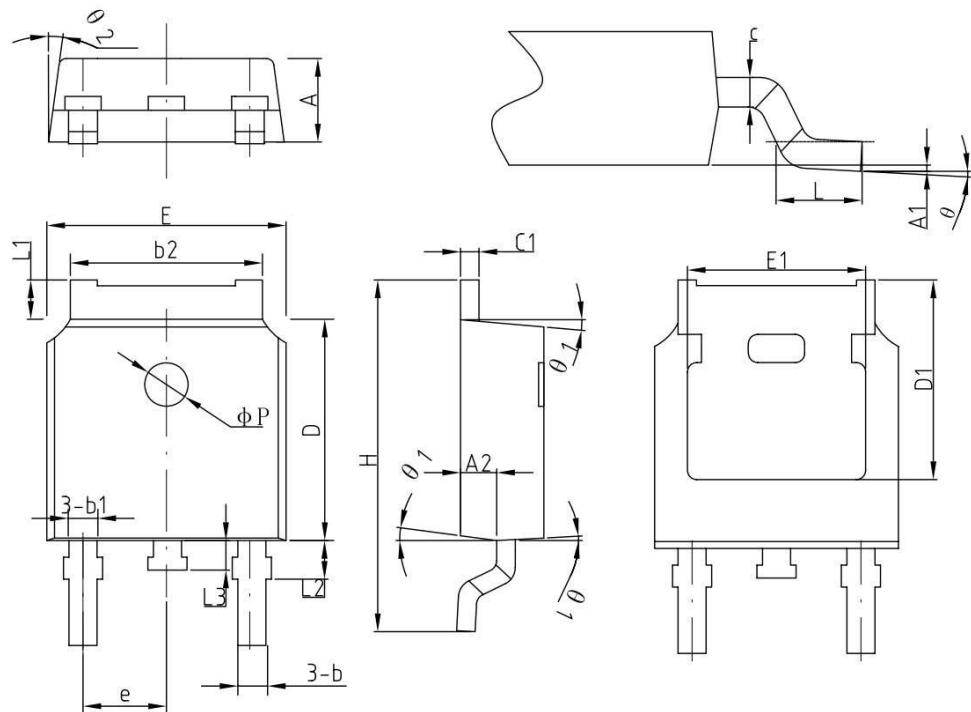
Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching Test Circuit & Waveforms


Peak Diode Recovery dv/dt Test Circuit & Waveforms


Package Dimension

TO-252

Unit: mm



COMMON DIMENSIONS
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	2.2	2.30	2.38
A1	0	—	0.10
A2	0.90	1.01	1.10
b	0.71	0.76	0.86
b1		0.76	
b2	5.13	5.33	5.46
c	0.47	0.50	0.60
c1	0.47	0.50	0.60
D	6.0	6.10	6.20
D1	—	5.30	—
E	6.50	6.60	6.70
E1	—	4.80	—
e		2.286BSC	
H	9.70	10.10	10.40
L	1.40	1.50	1.70
L1	0.90	—	1.25
L2		1.05	
L3		0.8	
φP		1.2	
θ	0°	—	8°
θ 1	5°	7°	9°
θ 2	5°	7°	9°